

# Search Notes



Application/Control No.

10/602,570

Examiner

Sun J. Lin

Applicant(s)/Patent under  
Reexamination

GRINCHUK ET AL.

Art Unit

2825

## SEARCHED

Class	Subclass	Date	Examiner
716	18	2/16/2005	JSL
716	2	2/16/2005	JSL
716	1	2/16/2005	JSL
716	7	2/16/2005	JSL
326	104	2/16/2005	JSL
326	10	2/16/2005	JSL

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
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EAST  
[USPAT;US-  
PGPUB;UPO;JPO;DERWENT;IBM\_T  
DB] 2/16/2005 JSL

IEEE 2/16/2005 JSL

GOOGLE 2/16/2005 JSL